


<b>Search Notes</b> 	<b>Application/Control No.</b> 10761403	<b>Applicant(s)/Patent Under Reexamination</b> MIYAO ET AL.
	<b>Examiner</b> John Chavis	<b>Art Unit</b> 2193

SEARCHED			
Class	Subclass	Date	Examiner
717	145	320/08	jc

SEARCH NOTES		
Search Notes	Date	Examiner
West (IBM TDB, DERWENT, EPO, JPO, USPAT, PGPUBS) anded with word search	3/20/08	jc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner